



8N100-FC

Power MOSFET

8A, 1000V N-CHANNEL POWER MOSFET

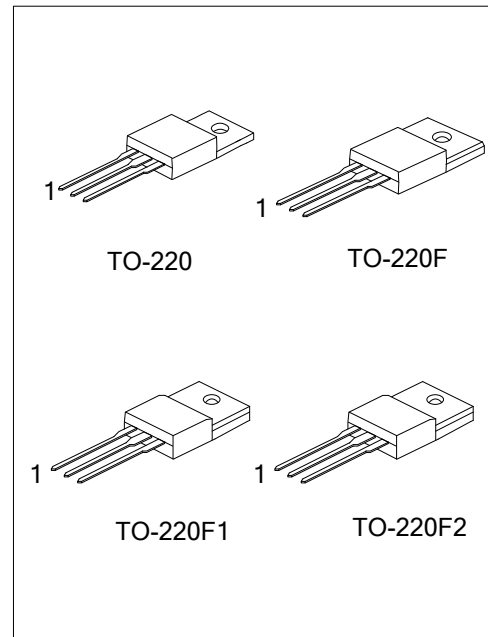
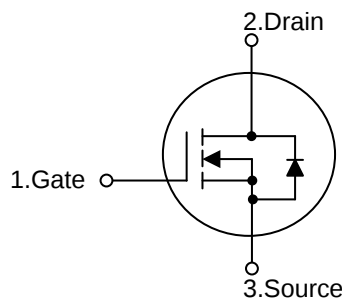
DESCRIPTION

The UTC 8N100-FC provide excellent $R_{DS(ON)}$, low gate charge and operation with low gate voltages. This device is suitable for use as a load switch or in PWM applications.

FEATURES

- * $R_{DS(ON)} \leq 2.0 \Omega$ @ $V_{GS}=10V$, $I_D=4.0A$
- * Fast Switching Capability
- * Avalanche Energy Specified

SYMBOL



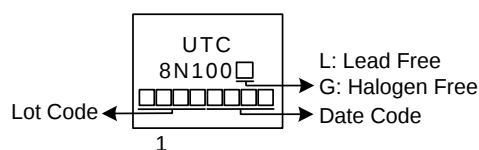
ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
8N100L-TA3-T	8N100G-TA3-T	TO-220	G	D	S	Tube
8N100L-TF1-T	8N100G-TF1-T	TO-220F1	G	D	S	Tube
8N100L-TF2-T	8N100G-TF2-T	TO-220F2	G	D	S	Tube
8N100L-TF3-T	8N100G-TF3-T	TO-220F	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

8N100G-TA3-T (1) Packing Type (2) Package Type (3) Green Package	(1) T: Tube (2) TA3: TO-220, TF1: TO-220F1, TF2: TO-220F1, TF3: TO-220F (3) G: Halogen Free and Lead Free, L: Lead Free
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MARKING



■ **ABSOLUTE MAXIMUM RATINGS** ($T_C = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	1000	V
Gate-Source Voltage		V_{GSS}	± 30	V
Drain Current	Continuous	I_D	8	A
	Pulsed (Note 2)	I_{DM}	16	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	252	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2.7	V/ns
Power Dissipation	TO-220	P_D	150	W
	TO-220F/TO-220F1		42	W
	TO-220F2			
Junction Temperature		T_J	+150	$^\circ\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^\circ\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating : Pulse width limited by maximum junction temperature.

3. $L=30\text{mH}$, $I_{AS}=4.1\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\ \Omega$, Starting $T_J = 25^\circ\text{C}$

4. $I_{SD} \leq 8.0\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$

■ **THERMAL DATA**

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient		θ_{JA}	62.5	$^\circ\text{C/W}$
Junction to Case	TO-220	θ_{JC}	0.83	$^\circ\text{C/W}$
	TO-220F/TO-220F1		2.97	$^\circ\text{C/W}$
	TO-220F2			

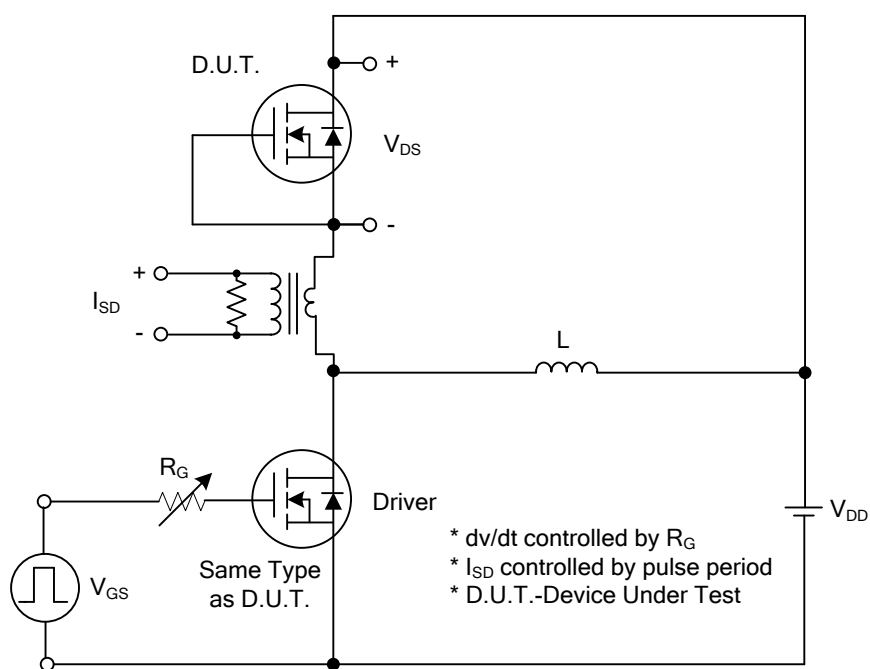
■ **ELECTRICAL CHARACTERISTICS** ($T_J = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	1000			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =1000V, V _{GS} =0V			10	μA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =±30V, V _{DS} =0V			±100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	3.0		5.0	V
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =4.0A			2.0	Ω
DYNAMIC CHARACTERISTICS						
Input Capacitance	C _{ISS}	V _{GS} =0V, V _{DS} =25V, f=1MHz		1500		pF
Output Capacitance	C _{OSS}			130		pF
Reverse Transfer Capacitance	C _{RSS}			3		pF
SWITCHING CHARACTERISTICS						
Total Gate Charge	Q _G	V _{DS} =100V, V _{GS} =10V, I _D =8A I _G =1mA (Note 1, 2)		34		nC
Gate-Source Charge	Q _{GS}			8		nC
Gate-Drain Charge	Q _{DD}			4		nC
Turn-On Delay Time	t _{D(ON)}	V _{DD} =100V, V _{GS} =10V, I _D =8A, R _G =25Ω (Note 1, 2)		23		ns
Turn-On Rise Time	t _R			17		ns
Turn-Off Delay Time	t _{D(OFF)}			74		ns
Turn-Off Fall Time	t _F			36		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Continuous Drain-Source Diode Forward Current	I _S				8	A
Maximum Pulsed Drain-Source Diode Forward Current	I _{SM}				16	A
Drain-Source Diode Forward Voltage	V _{SD}	I _S =8A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time	t _{rr}	I _S =8A, V _{GS} =0V, dI _F /dt=100A/μs		600		nS
Body Diode Reverse Recovery Charge	Q _{rr}			7		μC

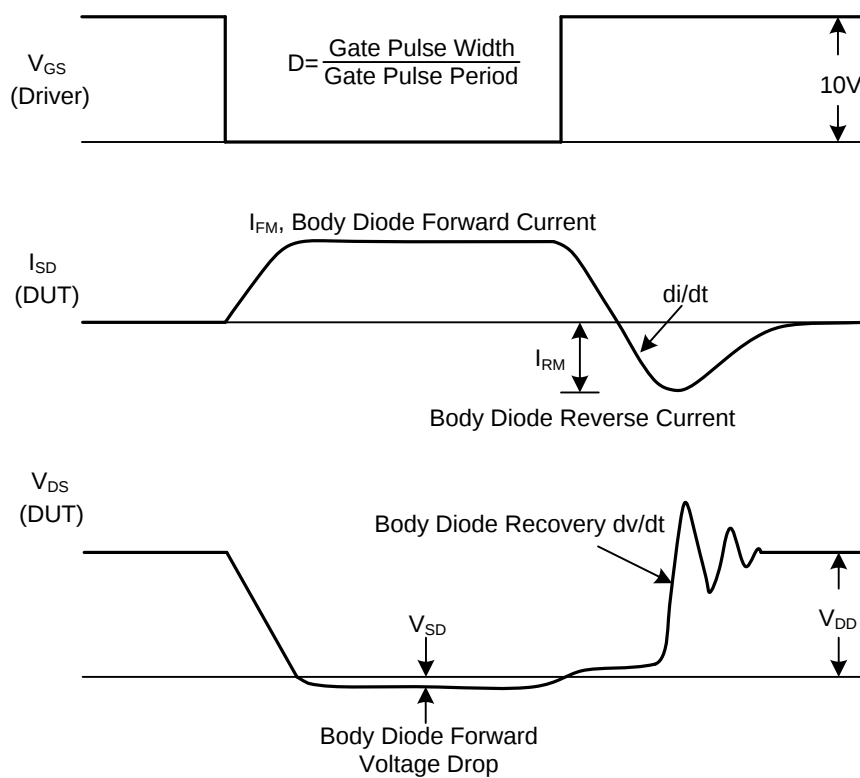
Notes: 1. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

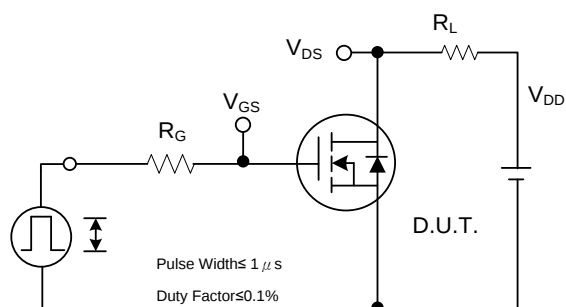


Peak Diode Recovery dv/dt Test Circuit

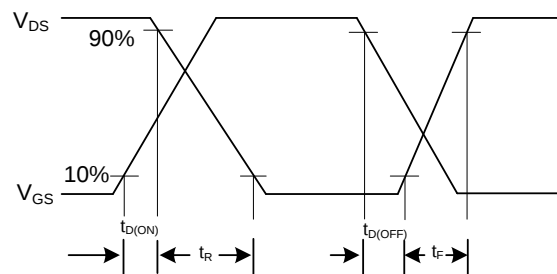


Peak Diode Recovery dv/dt Waveforms

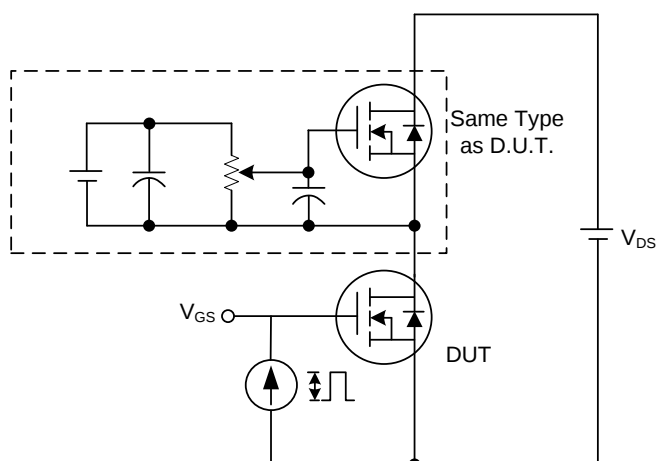
■ TEST CIRCUITS AND WAVEFORMS



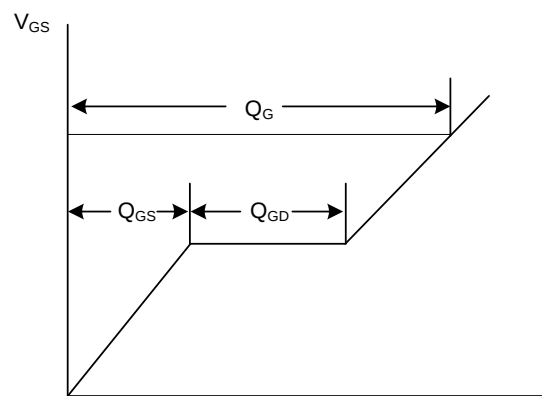
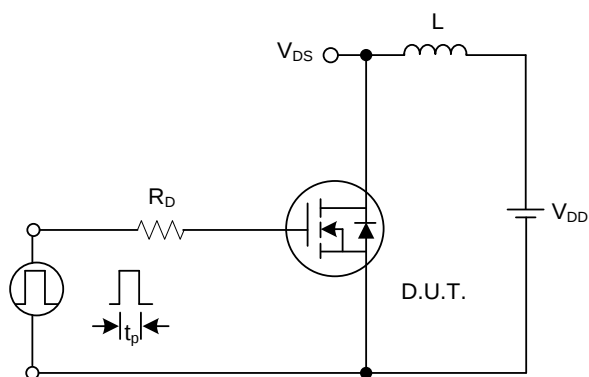
Switching Test Circuit



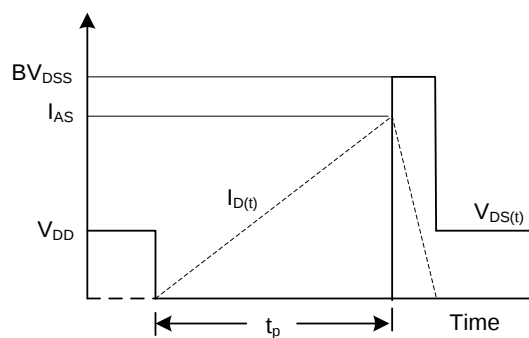
Switching Waveforms



Gate Charge Test Circuit

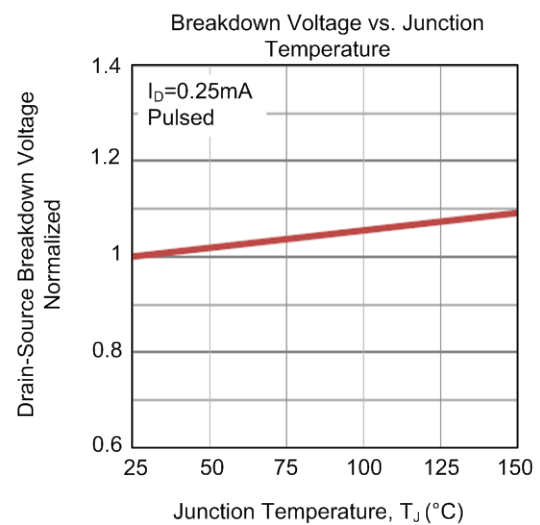
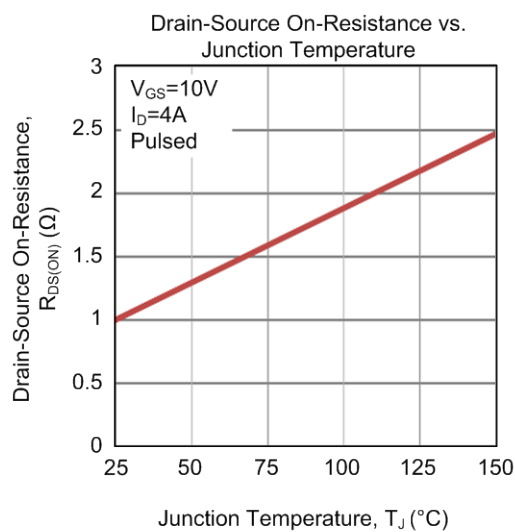
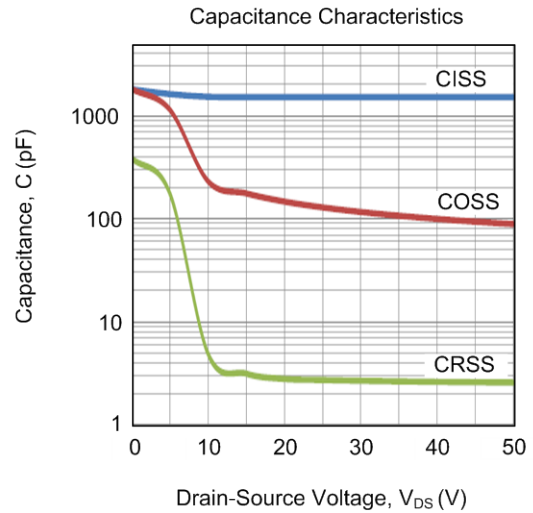
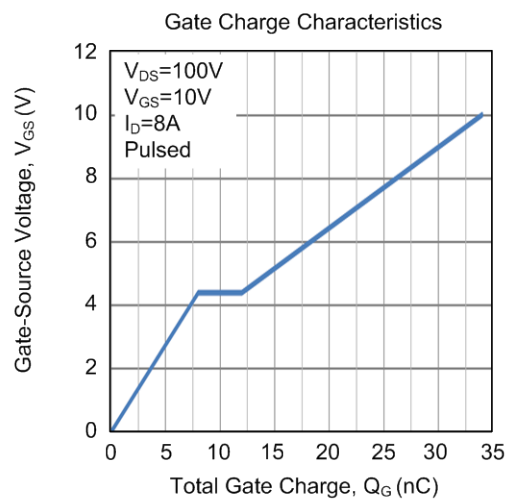
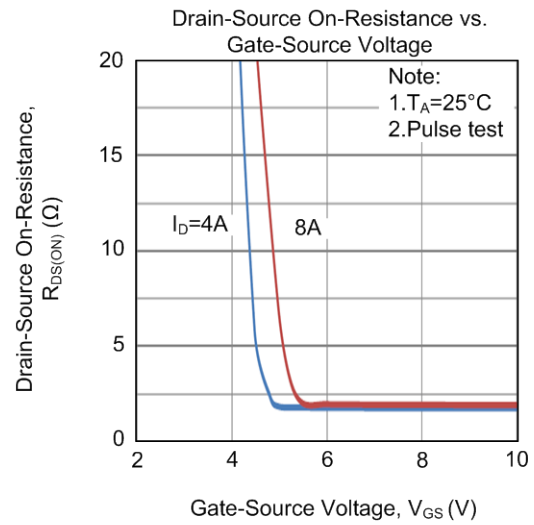
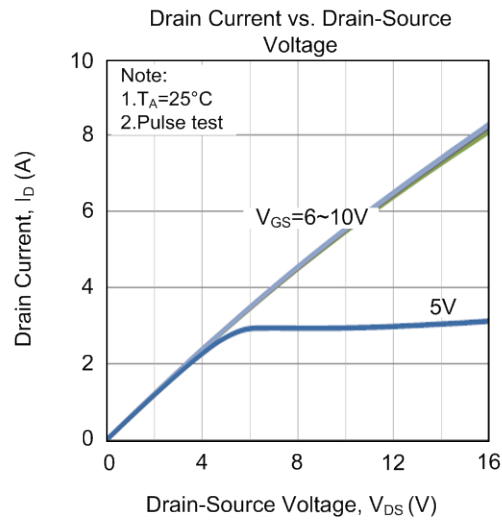
Charge
Gate Charge Waveform

Unclamped Inductive Switching Test Circuit

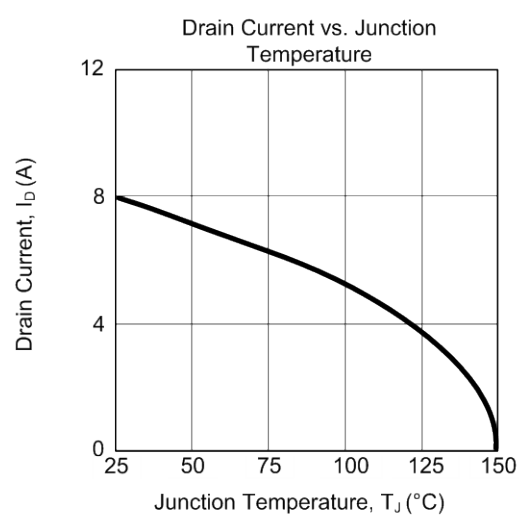
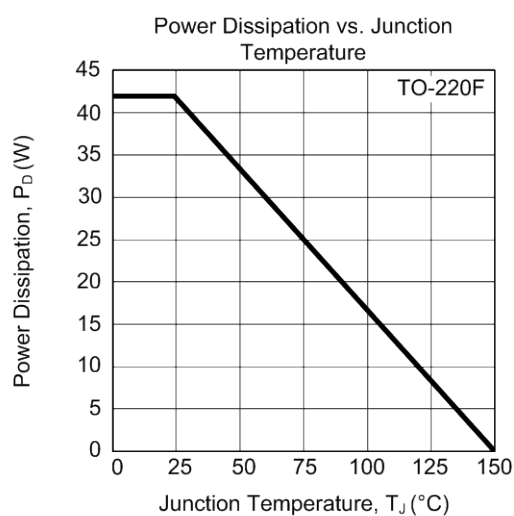
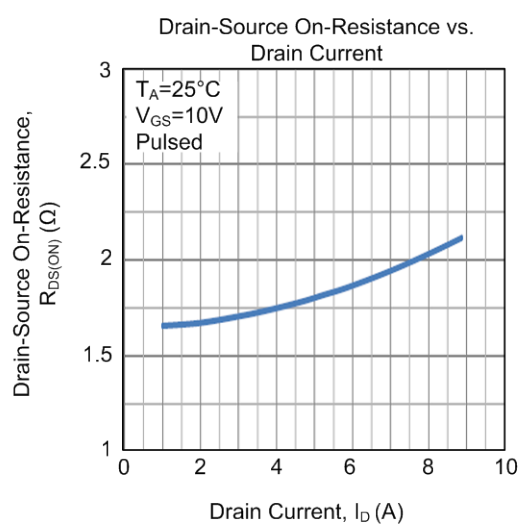
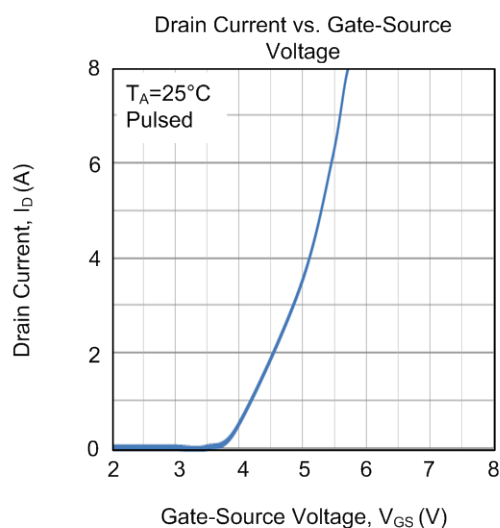
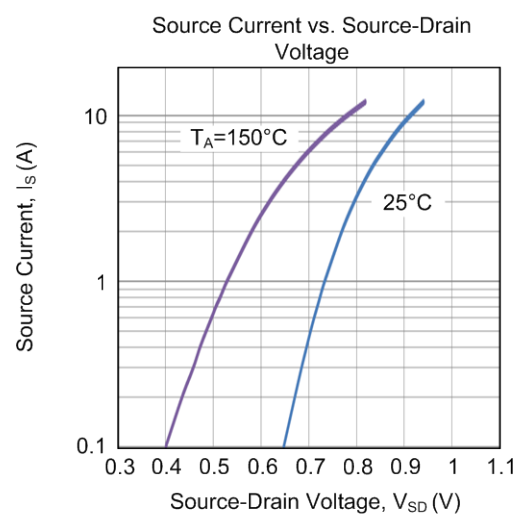
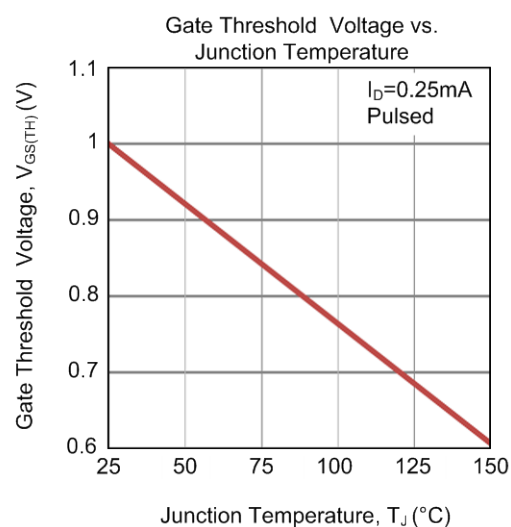


Unclamped Inductive Switching Waveforms

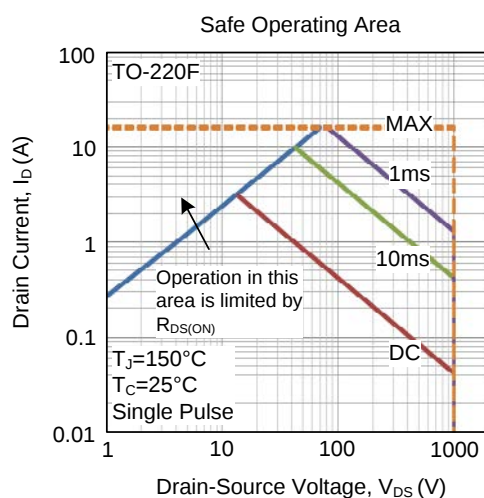
TYPICAL CHARACTERISTICS



■ TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



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